

Description

The AP60N02D uses advanced trench technology to provide excellent R_{DS(ON)}, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS}=20V I_D=60A

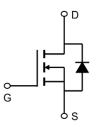
 $R_{DS(ON)} < 5.5 m\Omega$ @ V_{GS} =4.5V (Type: 4.1m Ω)

Application

Battery protection

Load switch

Uninterruptible power supply







Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)	
AP60N02D	TO-252-3L	AP60N02D XXX YYYY	2500	

Absolute Maximum Ratings (TC=25 ℃ unless otherwise noted)

Symbol	Parameter	Max.	Units
VDSS	Drain-Source Voltage	20	V
VGSS	Gate-Source Voltage	±12	V
ID@TA=25℃	Continuous Drain Current, VGS @ 4.5V	60	А
ID@TA=70℃	Continuous Drain Current, VGS @ 4.5V	42	А
IDM	Pulsed Drain Current note1	210	А
EAS	Single Pulsed Avalanche Energy note2	56.2	mJ
PD@TA=25℃	Power Dissipation	57	W
RθJC	Thermal Resistance, Junction to Case	2.63	°C/W
TJ, TSTG	Operating and Storage Temperature Range -55 to +175		$^{\circ}$ C



Electrical Characteristics (T_C=25°C, unless otherwise noted)

Symbol	Parameter Test Condition		Min.	Тур.	Max.	Units	
V(BR)DSS	Drain-Source Breakdown Voltage	Drain-Source Breakdown Voltage VGS=0V, ID=250µA		24	1	V	
IDSS	Zero Gate Voltage Drain Current	VDS=20V, VGS=0V,	-	-	1.0	μΑ	
IGSS	Gate to Body Leakage Current	VDS=0V, VGS=±12V	-	-	±100	nA	
VGS(th)	Gate Threshold Voltage	VDS=VGS, ID=250μA	0.5	0.7	1.2	V	
DDC(on)		VGS=4.5V, ID=30A	-	4.1	5.5		
RDS(on)	Static Drain-Source on-Resistance note3	VGS=2.5V, ID=20A	-	7.4	9.0	mΩ	
Ciss	Input Capacitance	VDC 40V VCC 0V	-	2500	-	pF	
Coss	Output Capacitance	VDS=10V, VGS=0V, f = 1.0MHz	-	407	-	pF	
Crss	Reverse Transfer Capacitance	I = I.UIVINZ	-	386	-	pF	
Qg	Total Gate Charge	VDC 40V ID 20A	-	32	-	nC	
Qgs	Gate-Source Charge	VDS=10V, ID=30A, VGS=4.5V	-	3	-	nC	
Qgd	Gate-Drain("Miller") Charge	VOO=4.5V	-	11	1	nC	
td(on)	Turn-on Delay Time	\/DQ_40\/	-	17	•	ns	
tr	Turn-on Rise Time	VDS=10V, ID=30A, RGEN=3Ω,	-	49	-	ns	
td(off)	Turn-off Delay Time	VGS =4.5V	-	74	-	ns	
tf	Turn-off Fall Time	VOO =4.5 V	-	26	-	ns	
IS	Maximum Continuous Drain to Source Diode Forward Current			-	75	Α	
ISM	Maximum Pulsed Drain to Source Diode Forward Current			-	300	Α	
VSD	Drain to Source Diode Forward Voltage VGS = 0V, IS=30A		-	-	1.2	V	

Notes:

- 1、Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
- 2_{\times} The test condition is, VDD=10V, VG=4.5V, L=0.5mH, RG=25 Ω , IAS=15A
- 3. The data tested by pulsed Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%
- 4. The power dissipation is limited by 150 $^{\circ}$ C junction temperature



Typical Characteristics

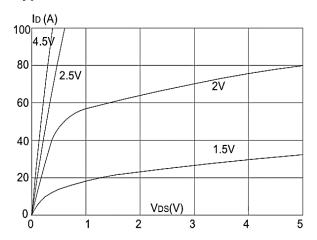


Figure1: Output Characteristics

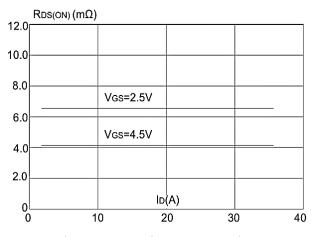


Figure 3:On-resistance vs. Drain Current

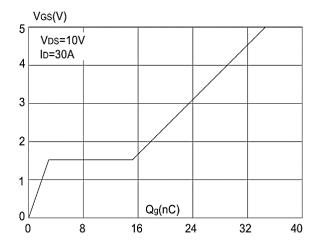


Figure 5: Gate Charge Characteristics

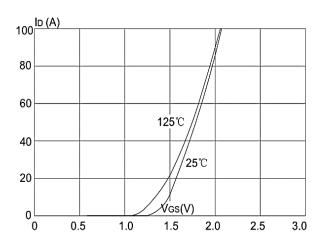


Figure 2: Typical Transfer Characteristics

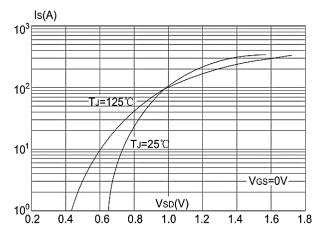


Figure 4: Body Diode Characteristics

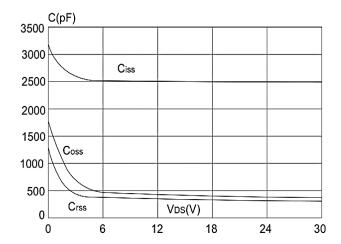


Figure 6: Capacitance Characteristics





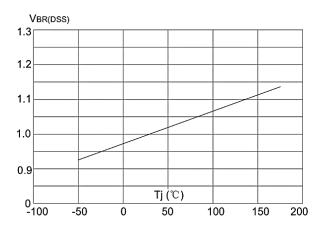


Figure 7: Normalized Breakdown Voltage vs.

Junction Temperature

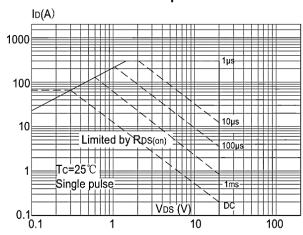


Figure 9: Maximum Safe Operating Area
Current
Temperature

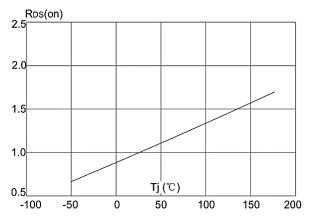


Figure 8: Normalized on Resistance vs

Junction Temperature

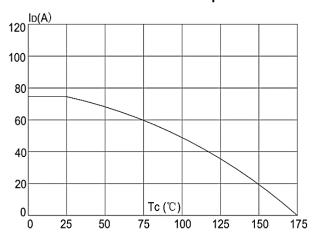


Figure 10: Maximum Continuous Drain vs. Case

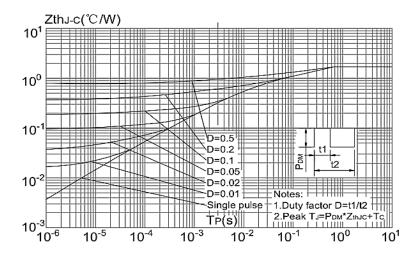
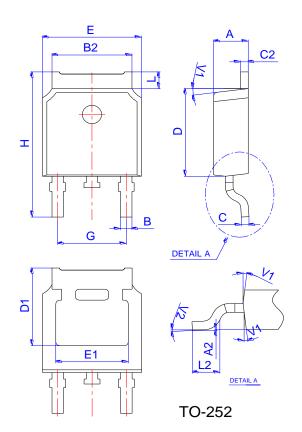


Figure.11: Maximum Effective

Transient Thermal Impedance, Junction-to-Case

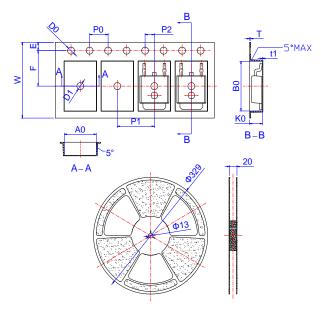


Package Mechanical Data:TO-252-3L



	Dimensions						
Ref.		Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.	
Α	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1	5.30REF			0.209REF			
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
Н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	

Reel Spectification-TO-252



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
В0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583





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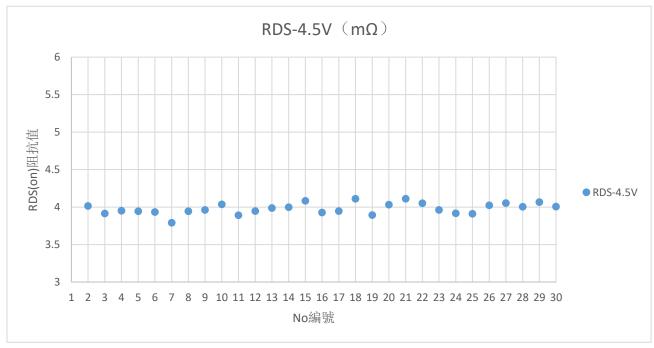


Edition	Date	Change
Rve3.8	2018/8/31	Initial release
Rve3.9	2019/11/31	Reduce RDS(on)
Rve4.0	2020/5/02	Change of specification format

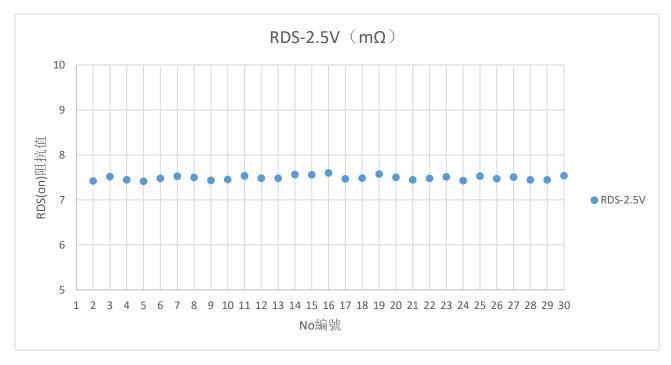
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Test Report For 30PCS (30pcs 典型測試報告)



Test: VGS=4.5V ID=30A



Test: VGS=2.5V ID=20A



